



Lecture 2: Case Study in Electronic System Design

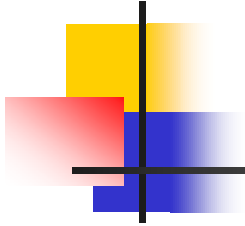
2011 Spring

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Outline

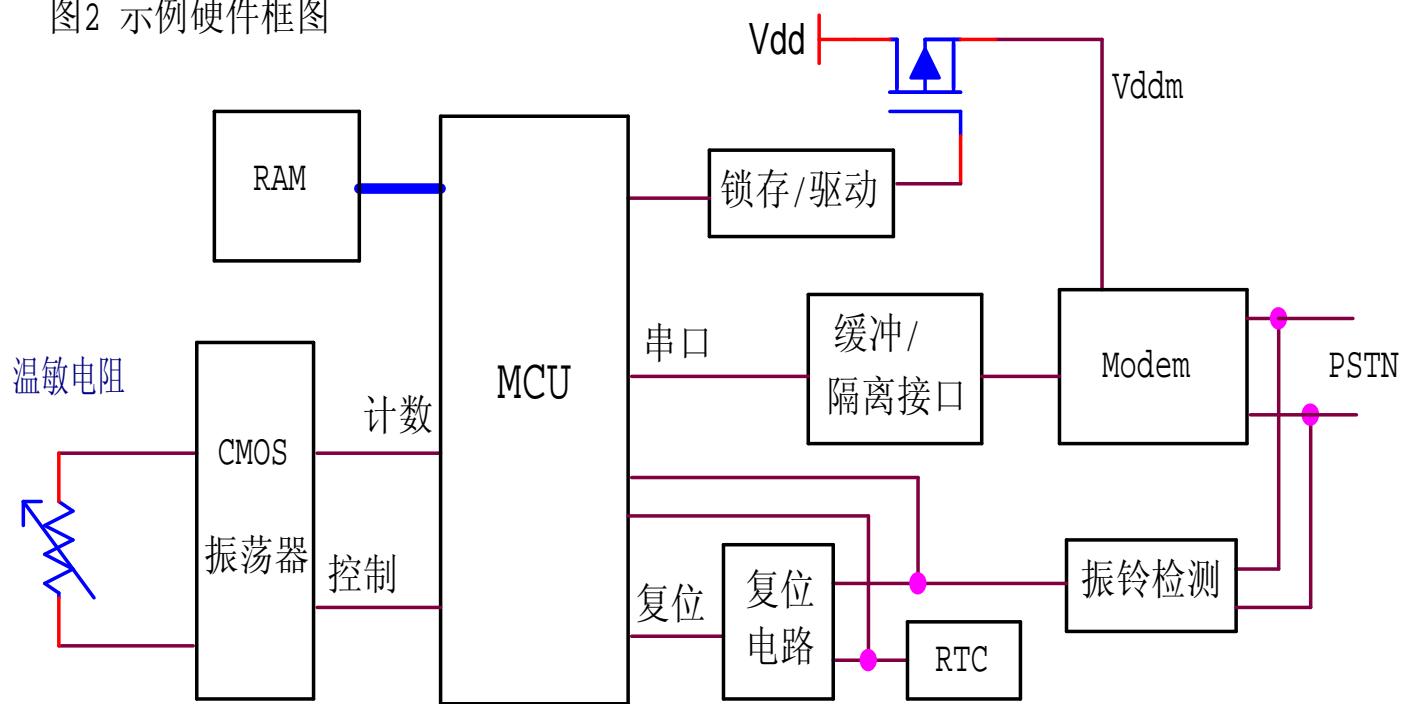
- n 1. Overview
- n 2. Design Methodology
- n 3. Case Study – Digital Frequency meter
 - n Case Study 1: System Requirement Analysis
 - n Case Study 2: System Design
 - n Case Study 3: Sub System Design
 - n Case Study 4: Software Design
 - n Case Study 5: System Test
 - n Case Study 6: Document
- n 4. Design Tips
- n 5. Summary



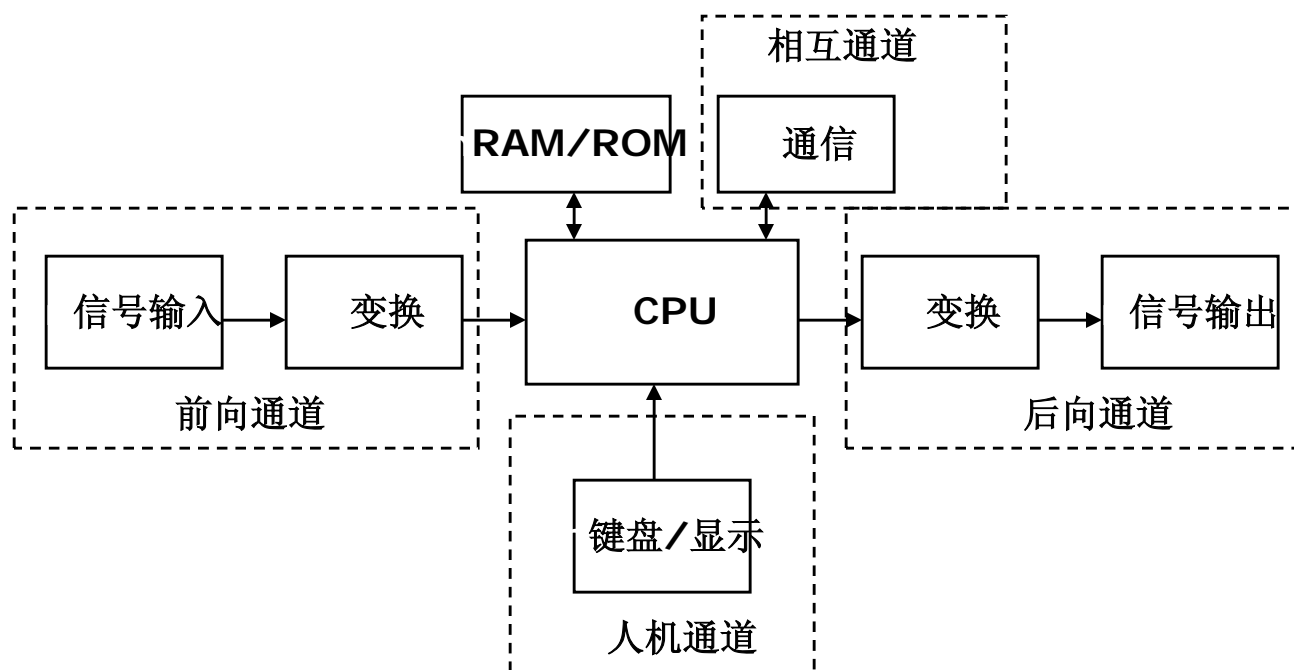
n 1. Overview

单片机为核心的电子系统

图2 示例硬件框图

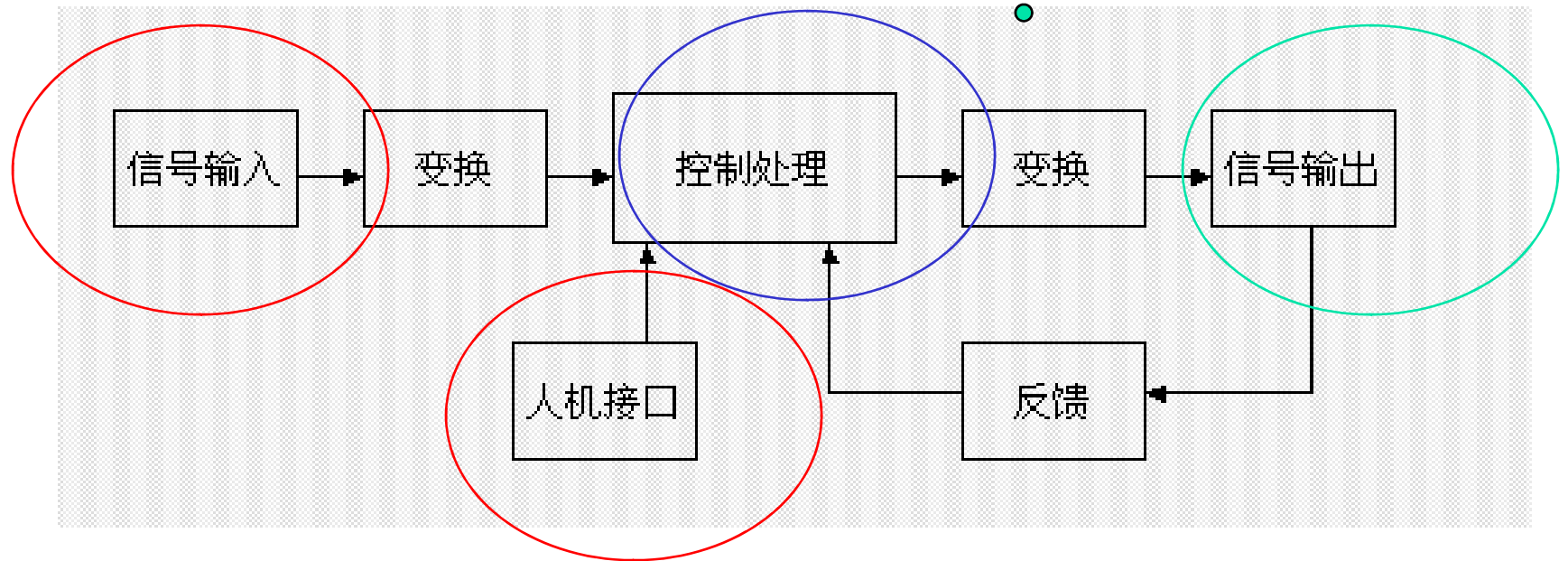


单片机为核心的电子系统：系统组成



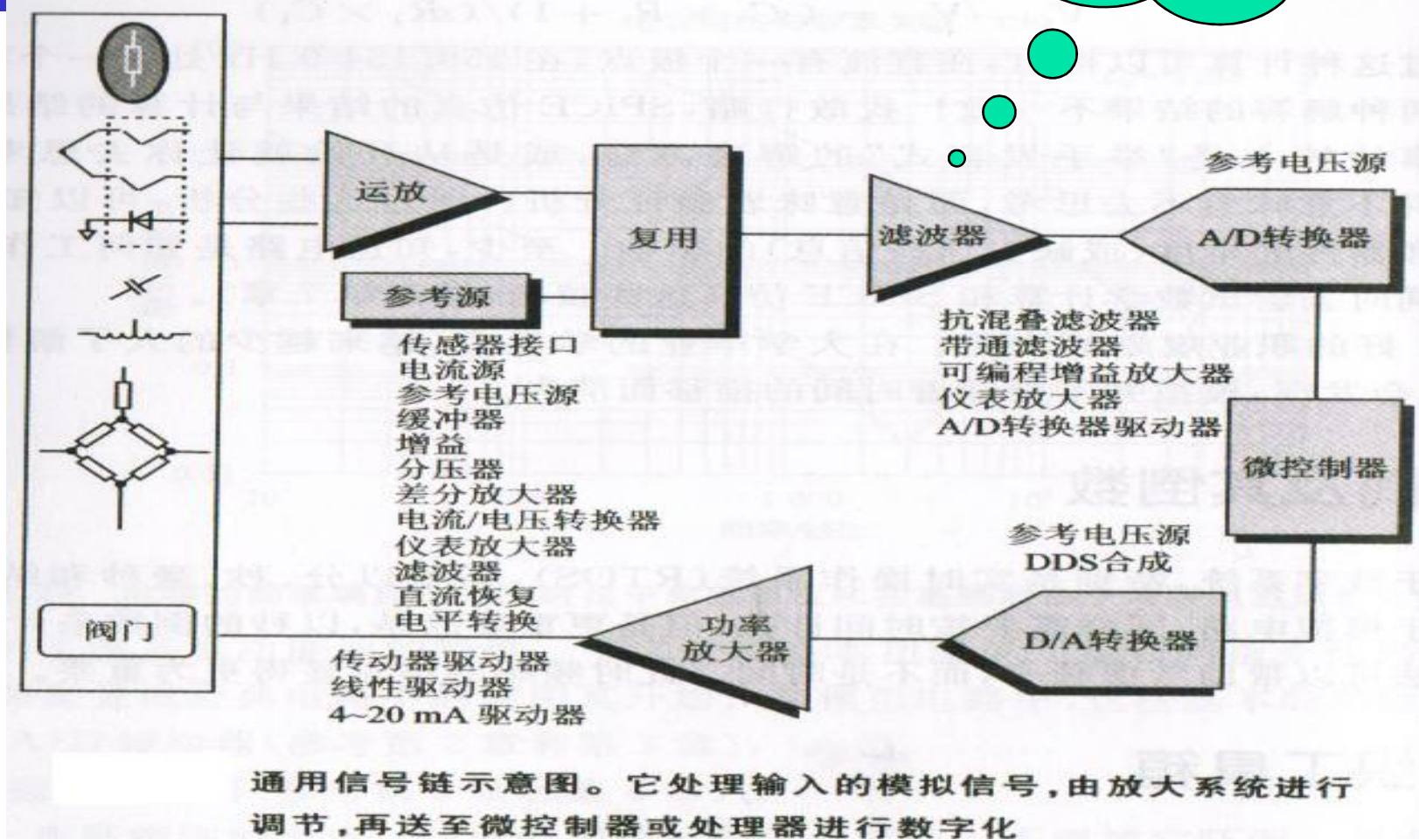
电子系统的组成

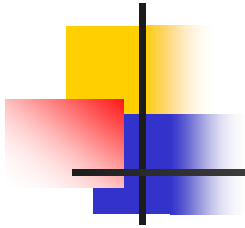
n系统指标



单片机为核心的电子系统： 信号流图

n系统指标

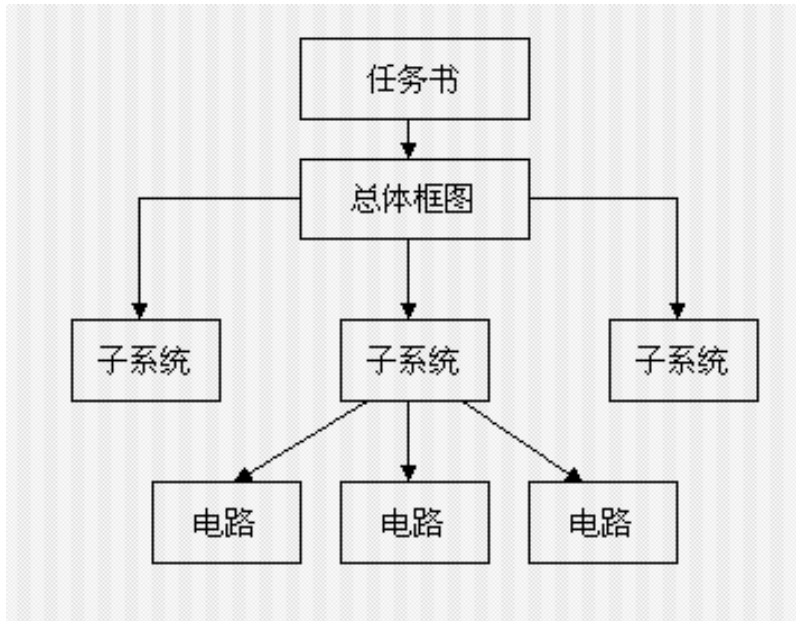




n 2. Design Methodology

1. 设计方法

Top Down

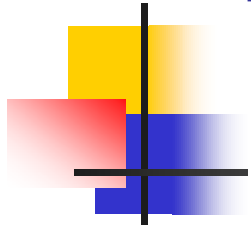


Bottom Up

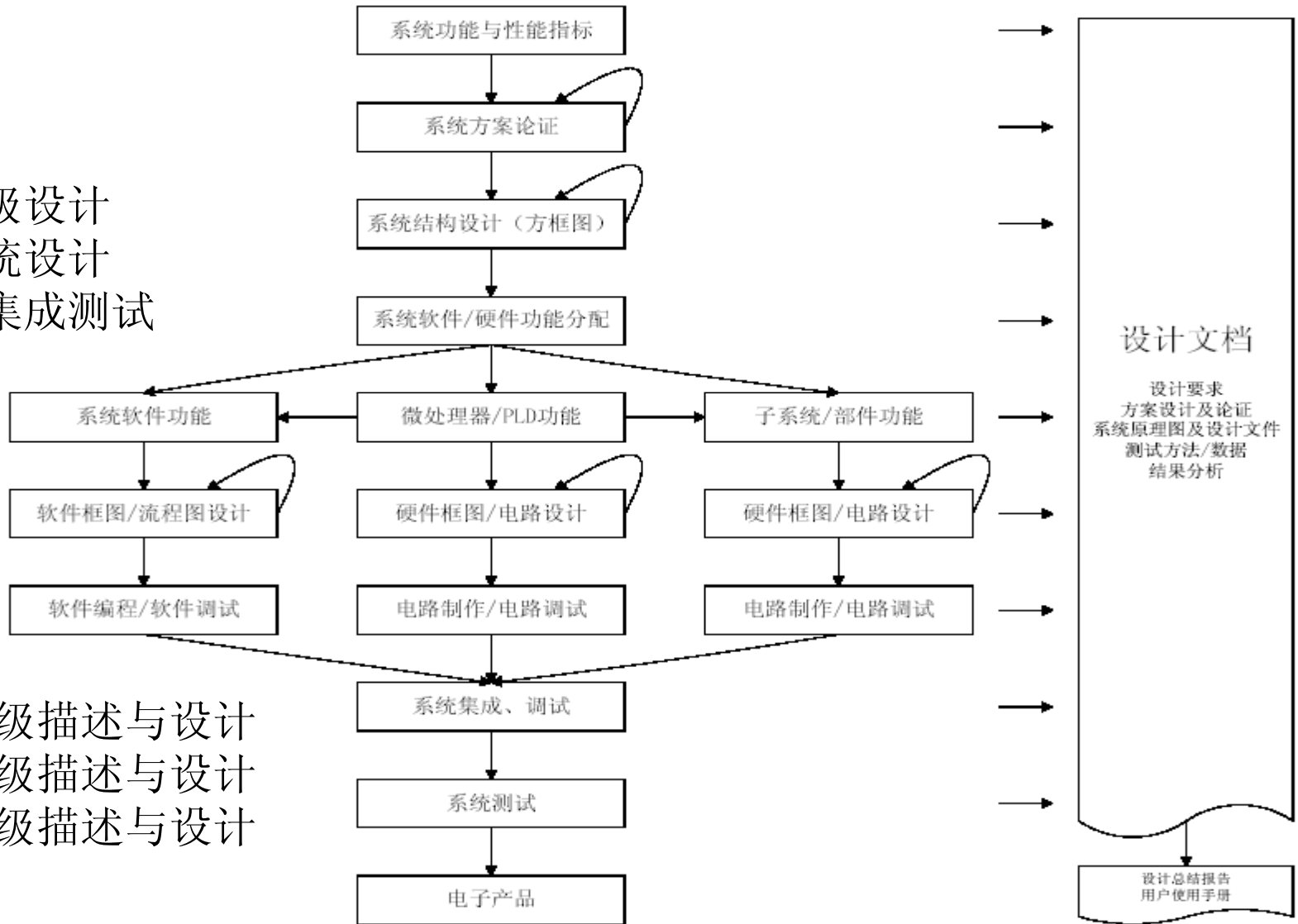
Debug
Integrate

- 功能要求
- 总体框图
- 子系统
- 单元电路
 - 选芯片
 - 原理图
 - 电路仿真
 - PCB图
 - 单元调试
- 系统调试
- 反复

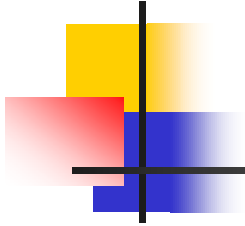
2. Process of Design



- 系统级设计
- 子系统设计
- 系统集成测试



- 行为级描述与设计
- 结构级描述与设计
- 物理级描述与设计



n 3. Case Study

3. Case Study:

Digital Frequency Meter

- n Case Study 1: System Requirement Analysis
- n Case Study 2: System Design
- n Case Study 3: Sub System Design
- n Case Study 4: Software Design
- n Case Study 5: System Test
- n Case Study 6: Document



3.1 Case 1 Digital

n System Re

1. 基本要求

(1) 频率测量

- a. 测量范围 信号：方波、正弦波；幅度：0.5V~5V；频率：1Hz~1MHz
- b. 测量误差 $\leq 0.1\%$

(2) 周期测量

- a. 测量范围 信号：方波、正弦波；幅度：0.5V~5V；频率：1Hz~1MHz
- b. 测量误差 $\leq 0.1\%$

(3) 脉冲宽度测量

- a. 测量范围 信号：脉冲波；幅度：0.5V~5V；脉冲宽度 $\geq 100\mu\text{s}$
- b. 测量误差 $\leq 1\%$

(4) 显示器

十进制数字显示，显示刷新时间1~10秒连续可调，对上述三种测量功能分别用不同颜色的发光二极管显示。

(5) 具有自校功能，时标信号频率为1MHz。

(6) 自行设计并制作满足本设计任务要求的稳压电源。

2. 发挥部分

(1) 扩展频率测量范围为0.1Hz~10MHz（信号幅度0.5V~5V），测量误差降低为0.01%（最大闸门 $\leq 10\text{s}$ ）。

(2) 测量并显示周期脉冲信号（幅度0.5V~5V、频率1Hz~1kHz）的占空比，占空比变化范围为90%，测量误差 $\leq 1\%$ 。

(3) 在1Hz~1MHz范围内及测量误差 $\leq 1\%$ 的条件下，进行小信号的频率测量，提出并实现抗干扰



3.1 Case Study 1: System Requirement Analysis

2 Requirement Analysis

- n Main Function
 - n Frequency/Period/Pulse Width/Duty
- n Main Specification
 - n Duty Error $\leq 1\%$, others Error $< 0.1\%$
 - n Frequency Range: 1Hz ~ 10MHz
 - n Advanced Function: 0.1Hz ~ 10MHz
 - n Pulse Width $\geq 100\mu\text{s}$
 - n Gate Time: 10s
 - n Refresh Display: 1 ~ 10s
 - n Input Level: 0.5 ~ 5V
 - n Advanced : 0.02V ~ 5V



3.2 Case Study 2: System Design

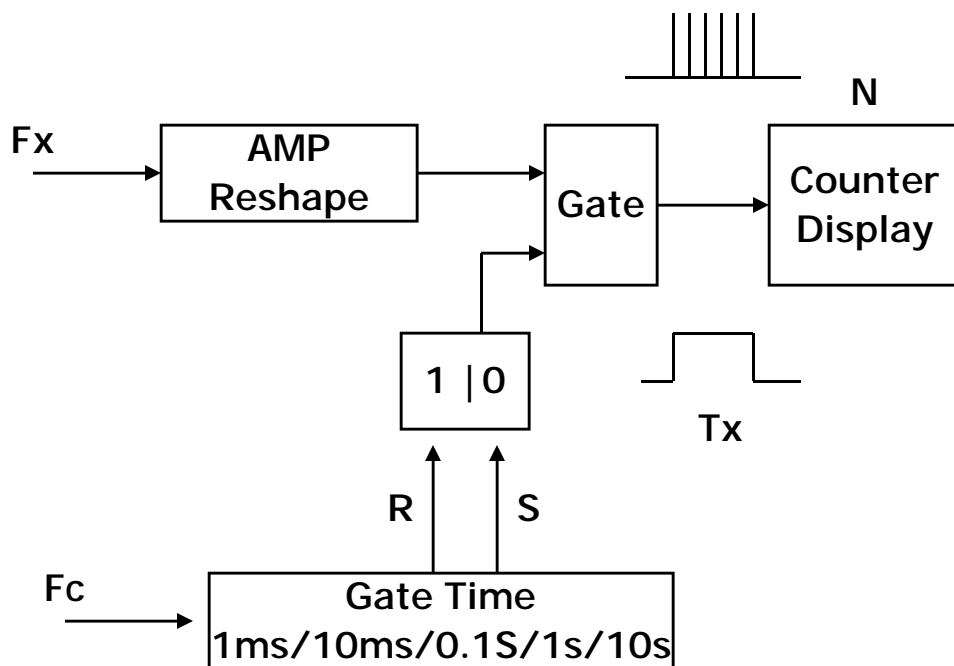
1. Measure Principle Study

- n Direct Algorithm
- n Indirect Algorithm
- n Multicycle Synchronization Algorithm

3.2 Case Study 2: System Design

2. Direct Algorithm for Frequency

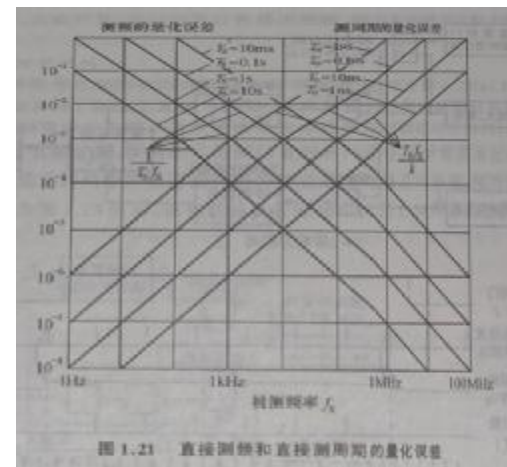
n Diagram



n Formula

$$F_x = N/T_x$$

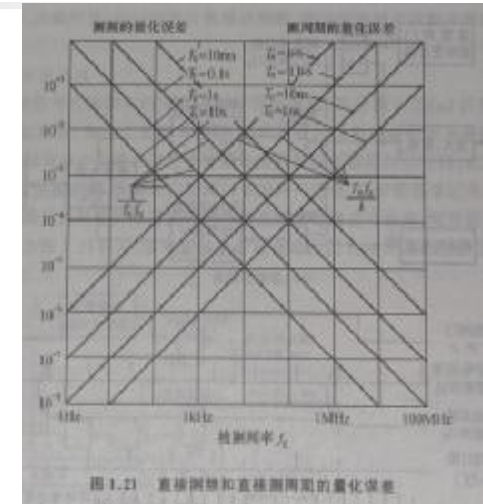
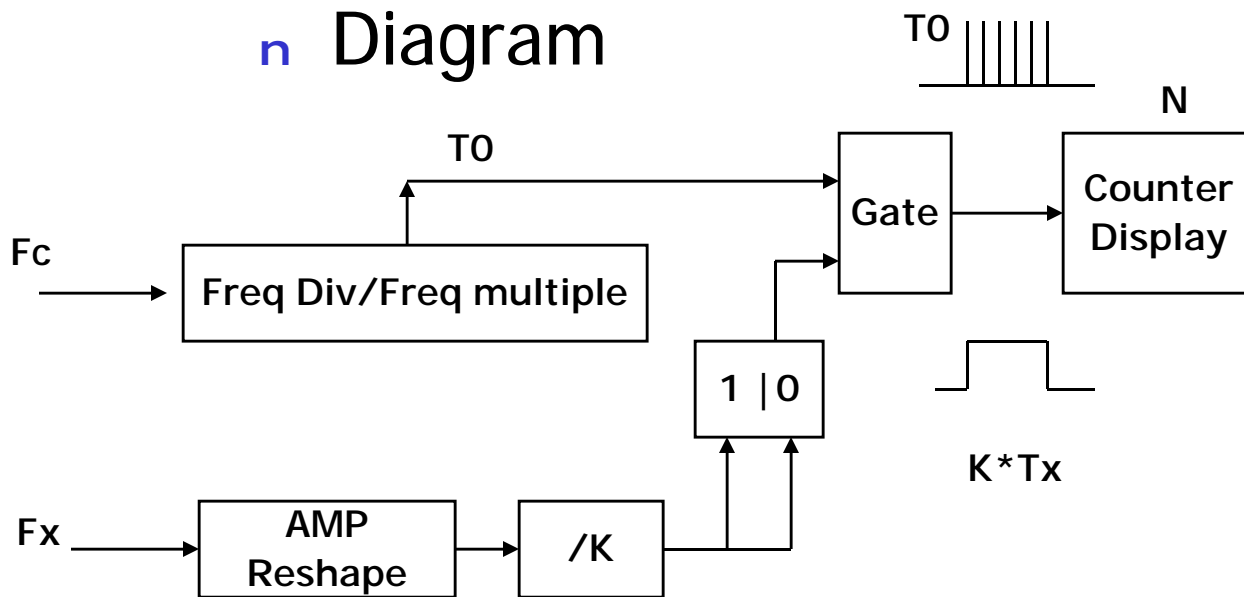
$$\Delta F_x/F_x = (1/T_s F_x + |\Delta F_c/F_c|)$$



3.2 Case Study 2: System Design

3. Direct Algorithm for Period

n Diagram



Trigger Error

n Formula

$$n \quad T_x = NT_0/K$$

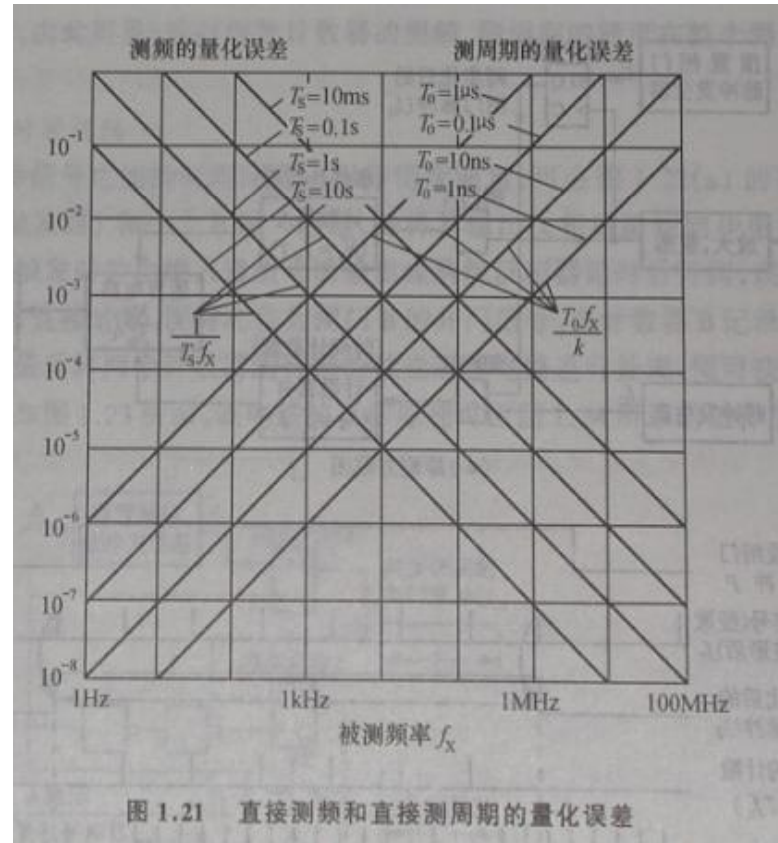
$$n \quad \Delta T_x/T_x = (T_0 F_x / K + |\Delta F_c / F_c| + 0.32 / K * \text{Power}(10, -\text{SNR} / 20))$$

3.2 Case Study 2: System Design

4. Indirect Algorithm for Freq/Period

- n Frequency \rightarrow Period
- n Period \rightarrow Frequency
- n Fm
 - n Middle Frequency

n Error Figure



3.2 Case Study 2: System Design

5. Multicycle Synchronization Algorithm

n Formula

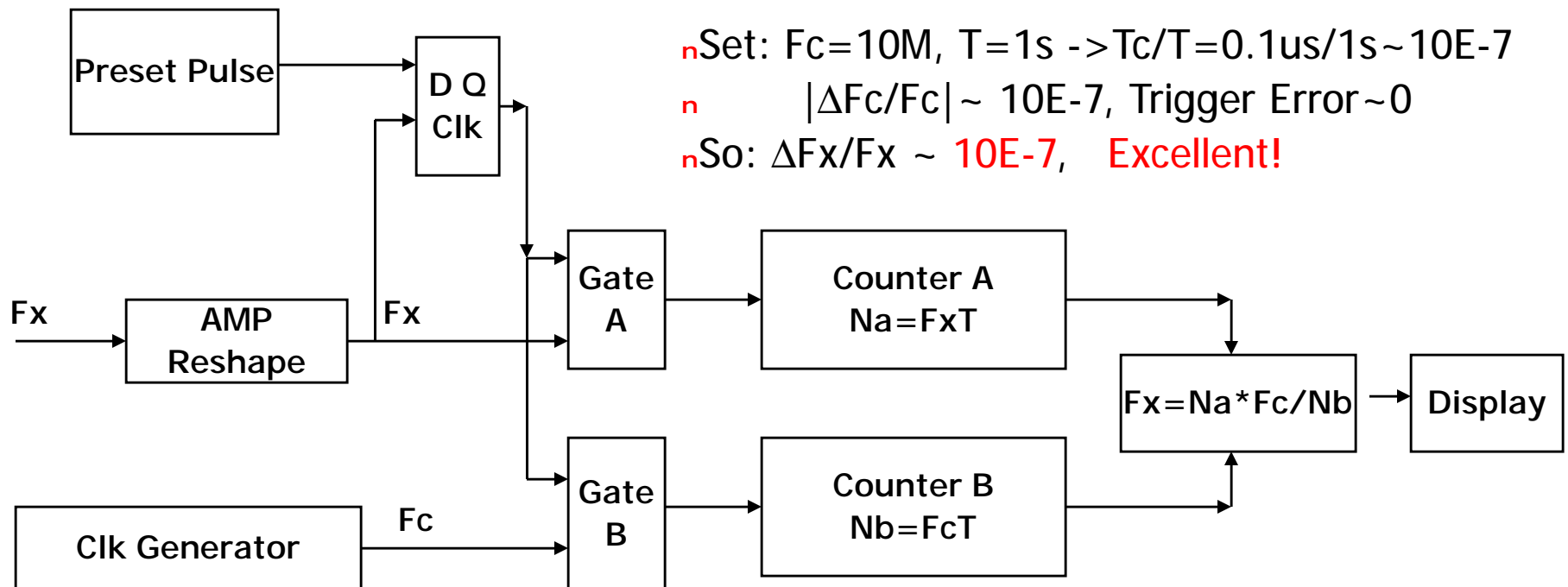
- n $F_x = N_a * F_c / N_b$
- n $\Delta F_x / F_x = \Delta T_x / T_x = T_c / T + |\Delta F_c / F_c| + 0.32 / K * \text{Power}(10, -\text{SNR} / 20)$

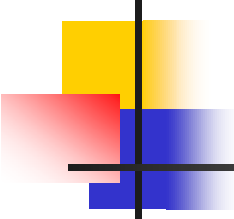
n Set: $F_c = 10\text{M}$, $T = 1\text{s}$ -> $T_c / T = 0.1\mu\text{s} / 1\text{s} \sim 10\text{E}-7$

n $|\Delta F_c / F_c| \sim 10\text{E}-7$, Trigger Error ~ 0

n So: $\Delta F_x / F_x \sim 10\text{E}-7$, **Excellent!**

n Diagram





3.2 Case Study 2: System Design

6. Core Algorithm Selection

Algorithm	Error	Complex	Software Req.
Direct	×	Low	No
Indirect	Enough	Middle	Switch @ Fm Division
M.S	Good	Middle	Division



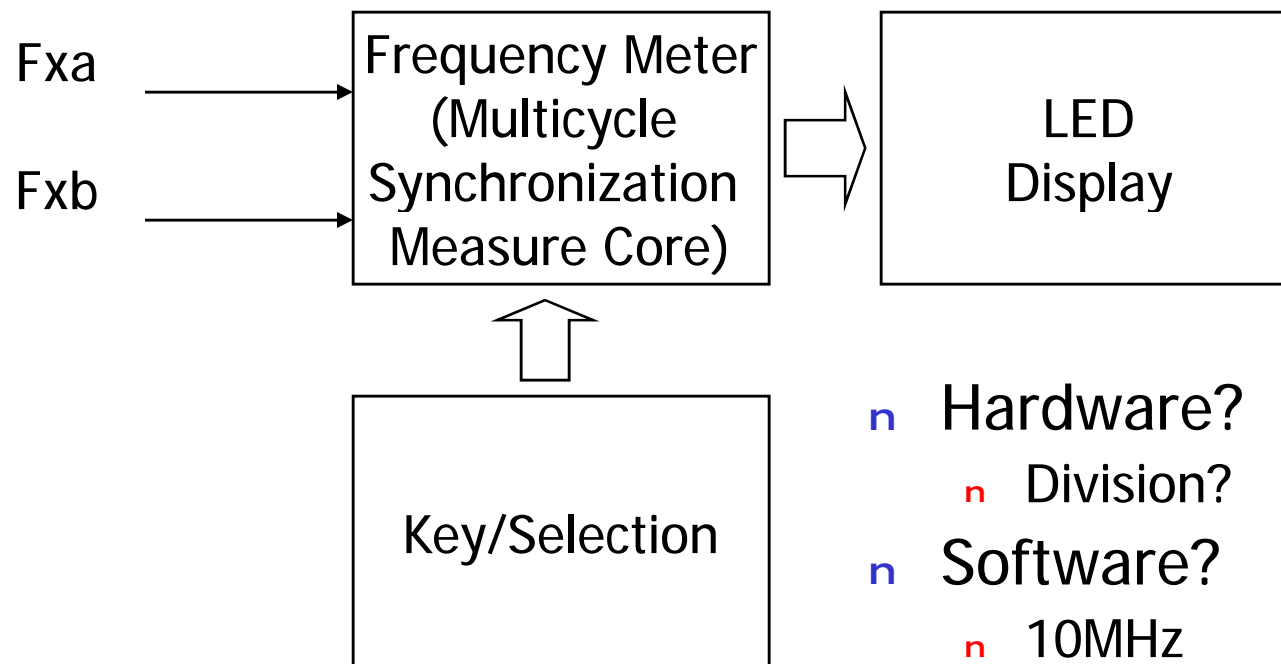
3.2 Case Study 2: System Design

6. Core Algorithm **Double Check**

- n Pulse Width
- n Duty
- n Advanced Requirement
- n Other Specifications...

3.2 Case Study 2: System Design

7. System Diagram(1)



n Hardware?

n Division?

n Software?

n 10MHz

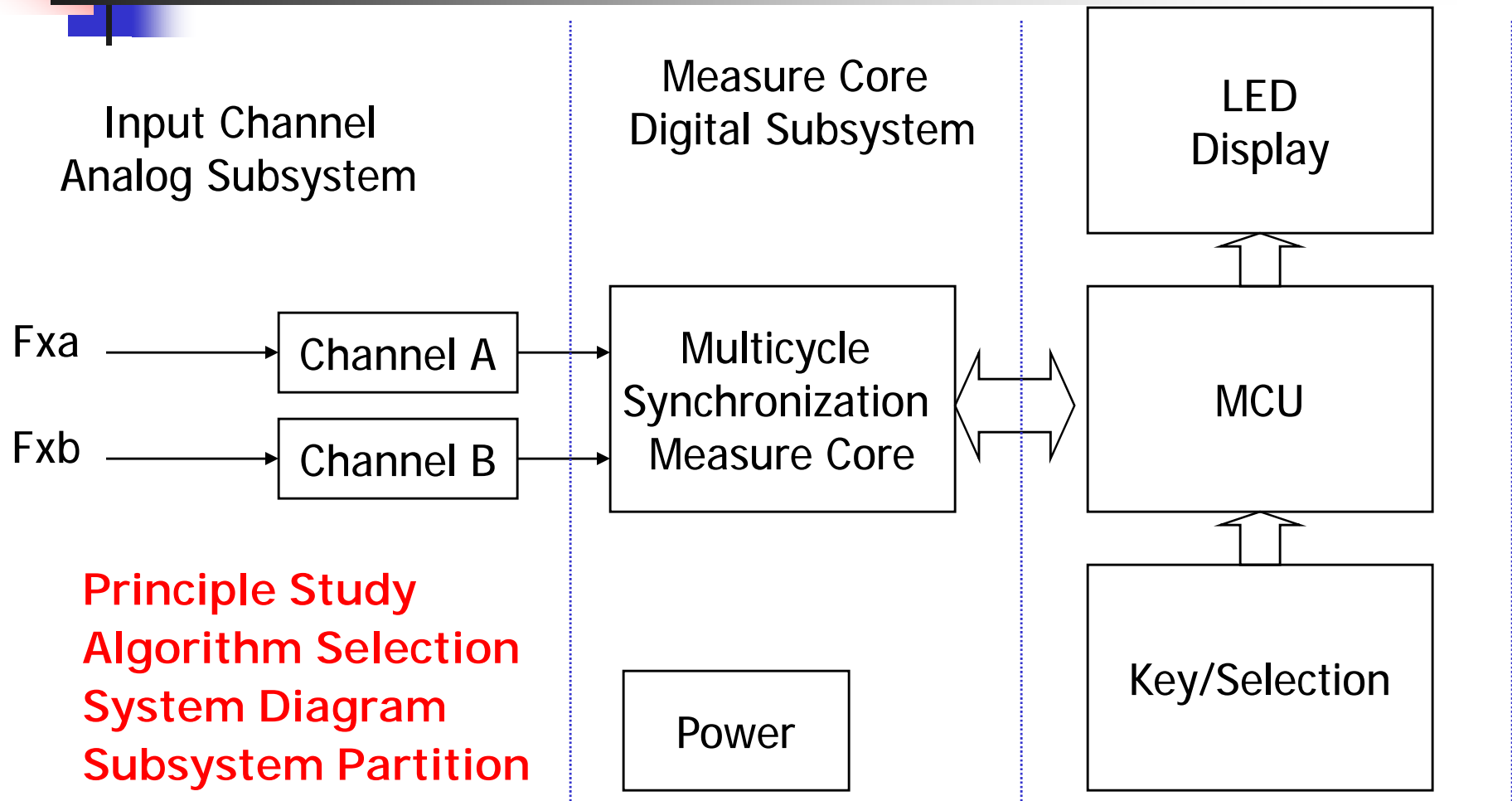
n Hardware/Software?

n 10MHz/Division

3.2 Case Study 2: System Design

7. System Diagram(2)

Controller
MCU Subsystem

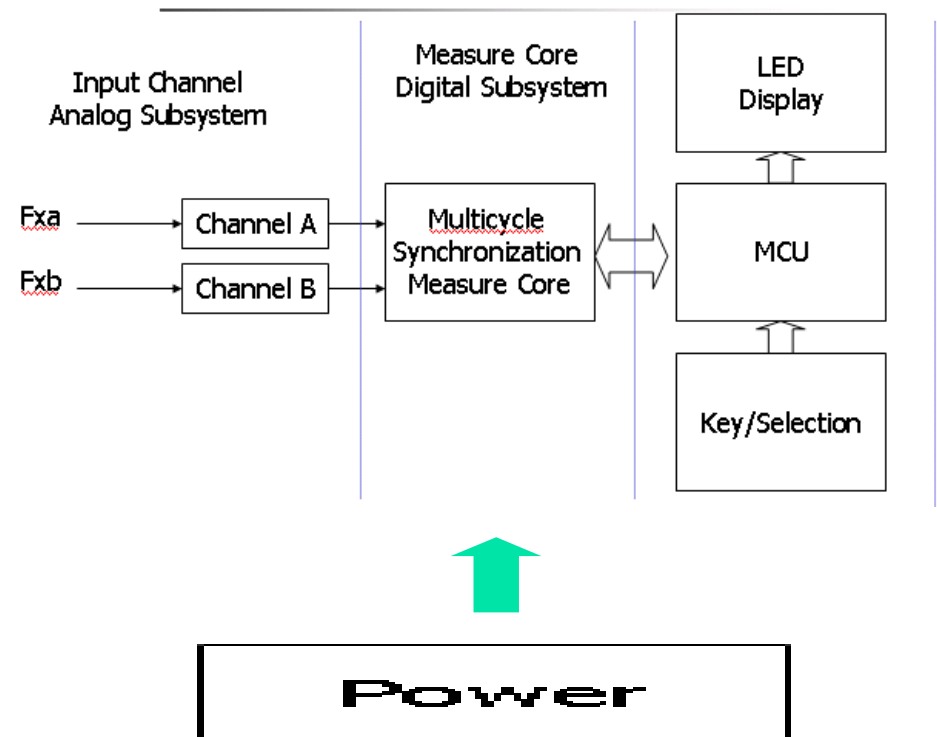


3.2 Case Study 2: System Design

7. System Diagram(3)

n Four Subsystems

- n Analog Subsystem
- n Digital Subsystem
- n MCU Subsystem
- n Power Subsystem





3.3 Case Study 3: Sub System Design(1)

- n Analog Subsystem
 - n Input Channel

3.3 Case Study 3: Sub System Design(1)

1. Input Channel Requirement

- n Type

- n Analog Subsystem

- n Requirement

- n Function

- n Convert Analog Signal to Digital Signal

- n Specification

- n Input signal

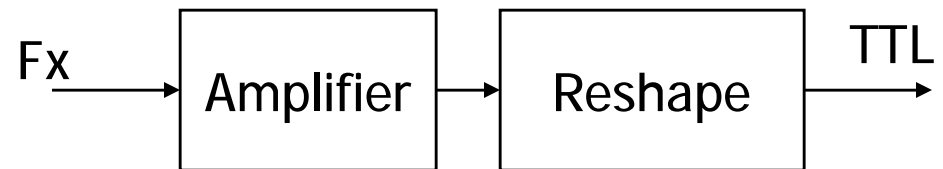
- n Level: 0.5V ~ 5V, **Advanced: 0.02V~5V**

- n Freq: 0.1Hz ~ 10MHz,

- n Output signal

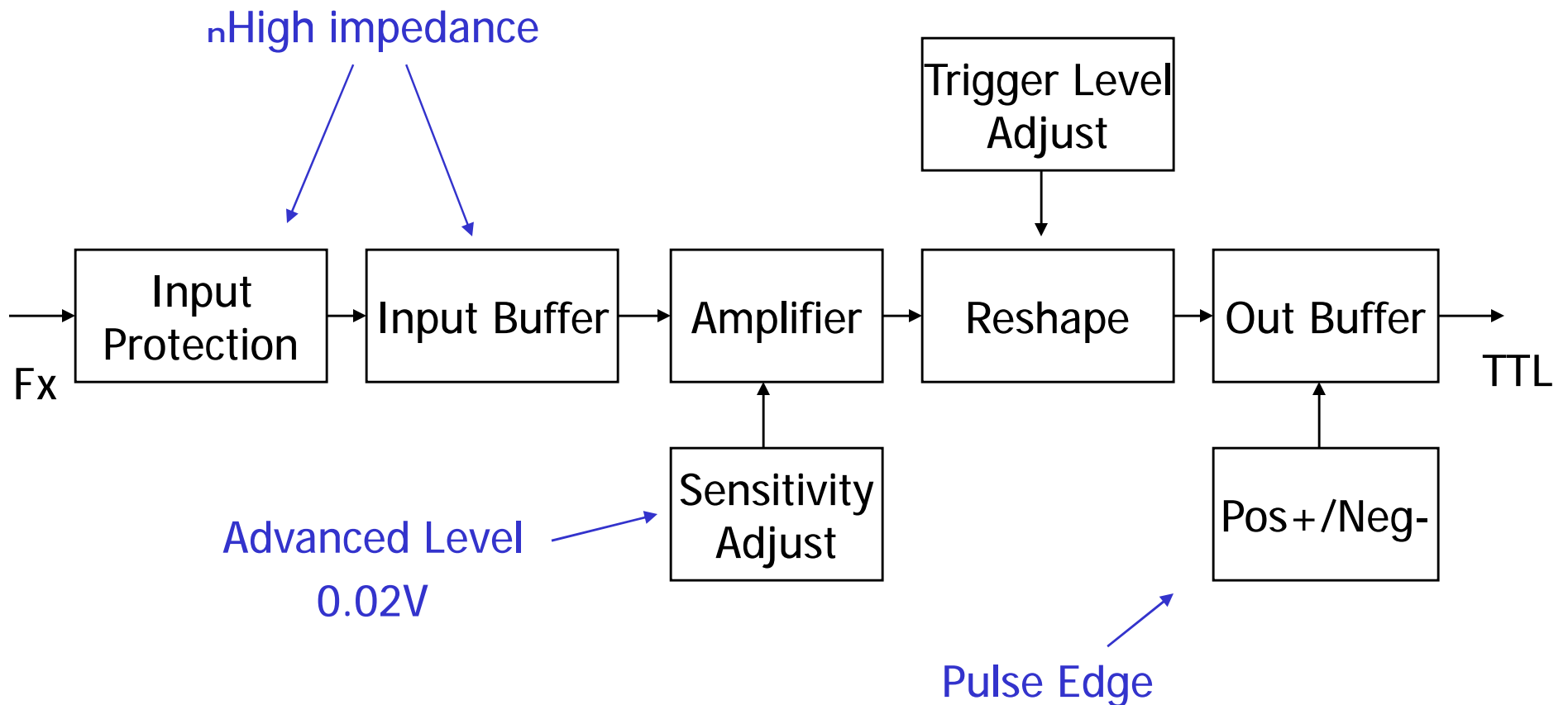
- n Level: TTL

- n Freq: 0.1Hz ~ 10MHz



3.3 Case Study 3: Sub System Design(1)

2. Input Channel Diagram



3.3 Case Study 3: Sub System Design(1)

3. Input Channel : Amplifier + Reshape

- n Reshape @ 0.02V input

- n TTL:

- n Trigger Level=2V

- n Gain = $2V/0.02V = 100$

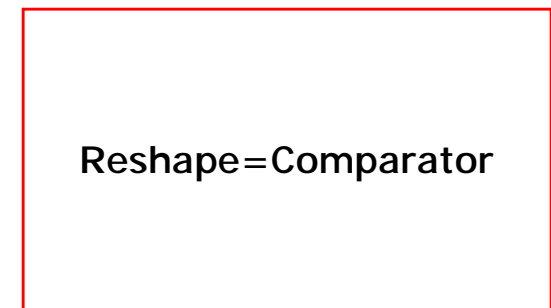
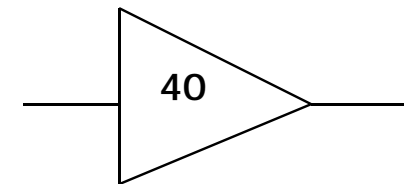
- n Comparator

- n MAX902 , SR=0.5V/s

- n $SR=2*\pi*F_x*U_m \Rightarrow U_m=0.8V @ F_x=0.1Hz$

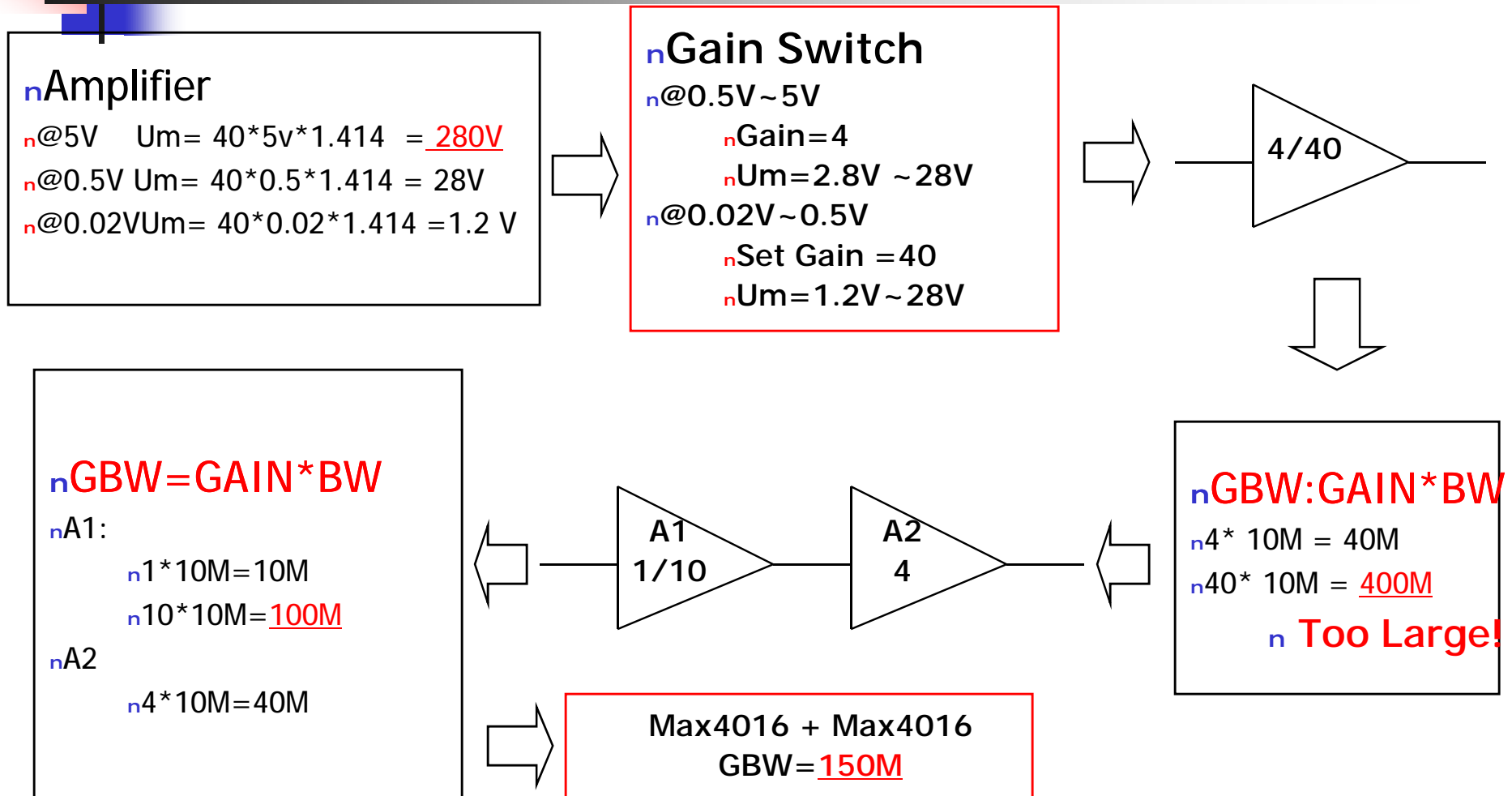
- n Gain = $0.8v/(0.02V* 1.414) = 30$

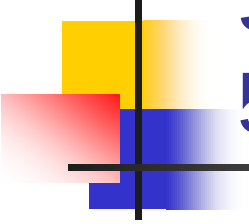
- n Choose Gain=40 @ 0.02 input



3.3 Case Study 3: Sub System Design(1)

4. Input Channel : Amplifier Double Check





3.3 Case Study 3: Sub System Design(1)

5. Analog Subsystem Design Main Points

- n Requirement Study & Analysis
- n Module Partition & Specification Assignment
- n Module Design
- n Couple Circuit Design
- n Specification Double Check



3.3 Case Study 3: Sub System Design(2)

n MCU Sub System

3.3 Case Study 3: Sub System Design(2)

1. Requirement for Controller

- n Setup
- n Display Frequency
- n Control Measure Core

- n Input:
 - n KeyIn
 - n Output:
 - n Digital display
 - n Status display
 - n Interface
 - n Read /write data with other modules
- Measure Core

Output

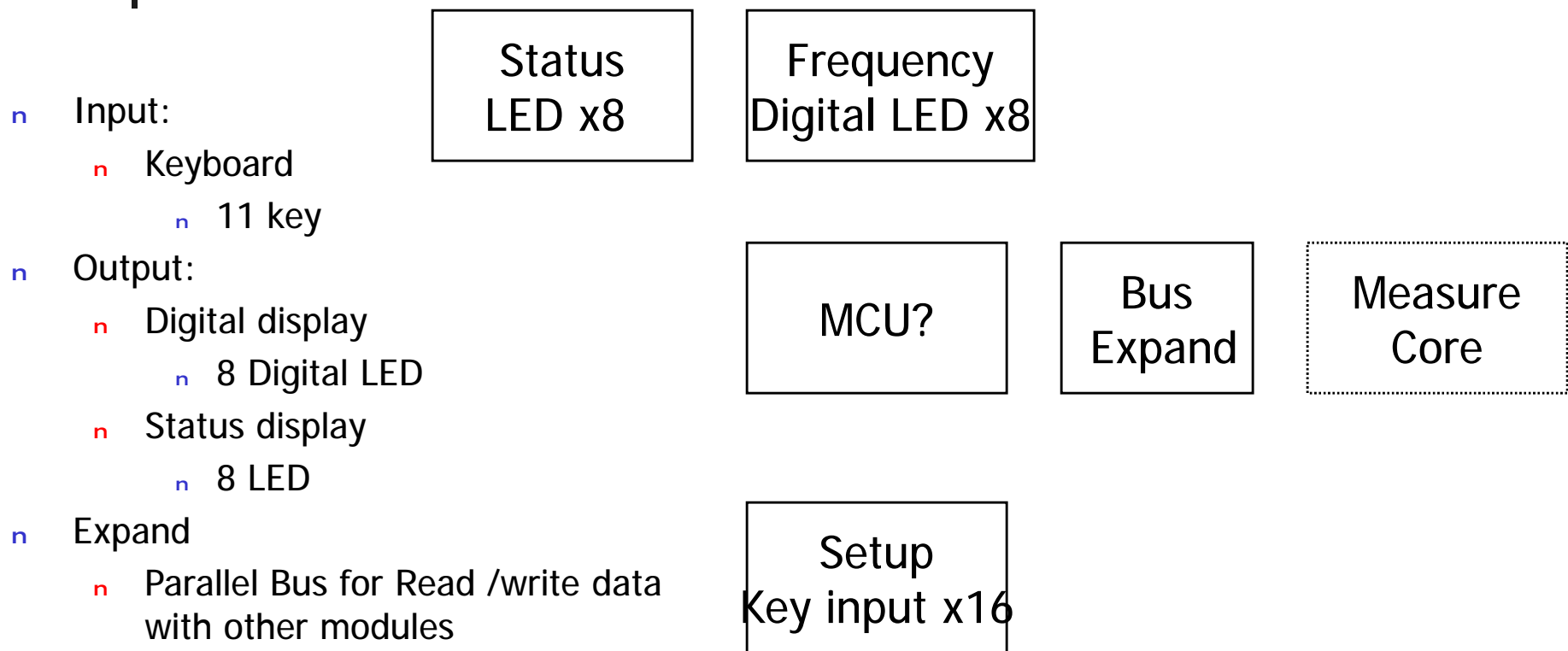
MCU

Interface

Input

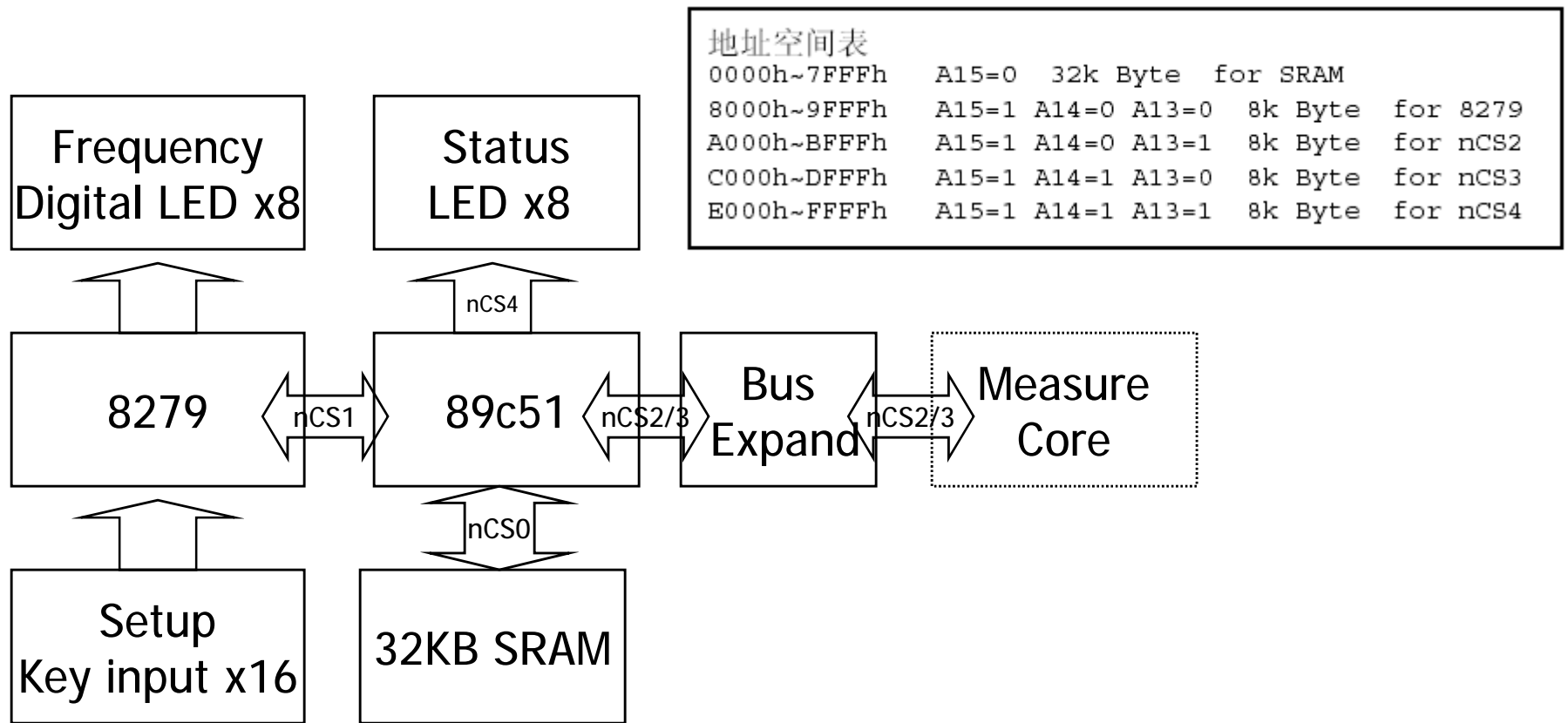
3.3 Case Study 3: Sub System Design(2)

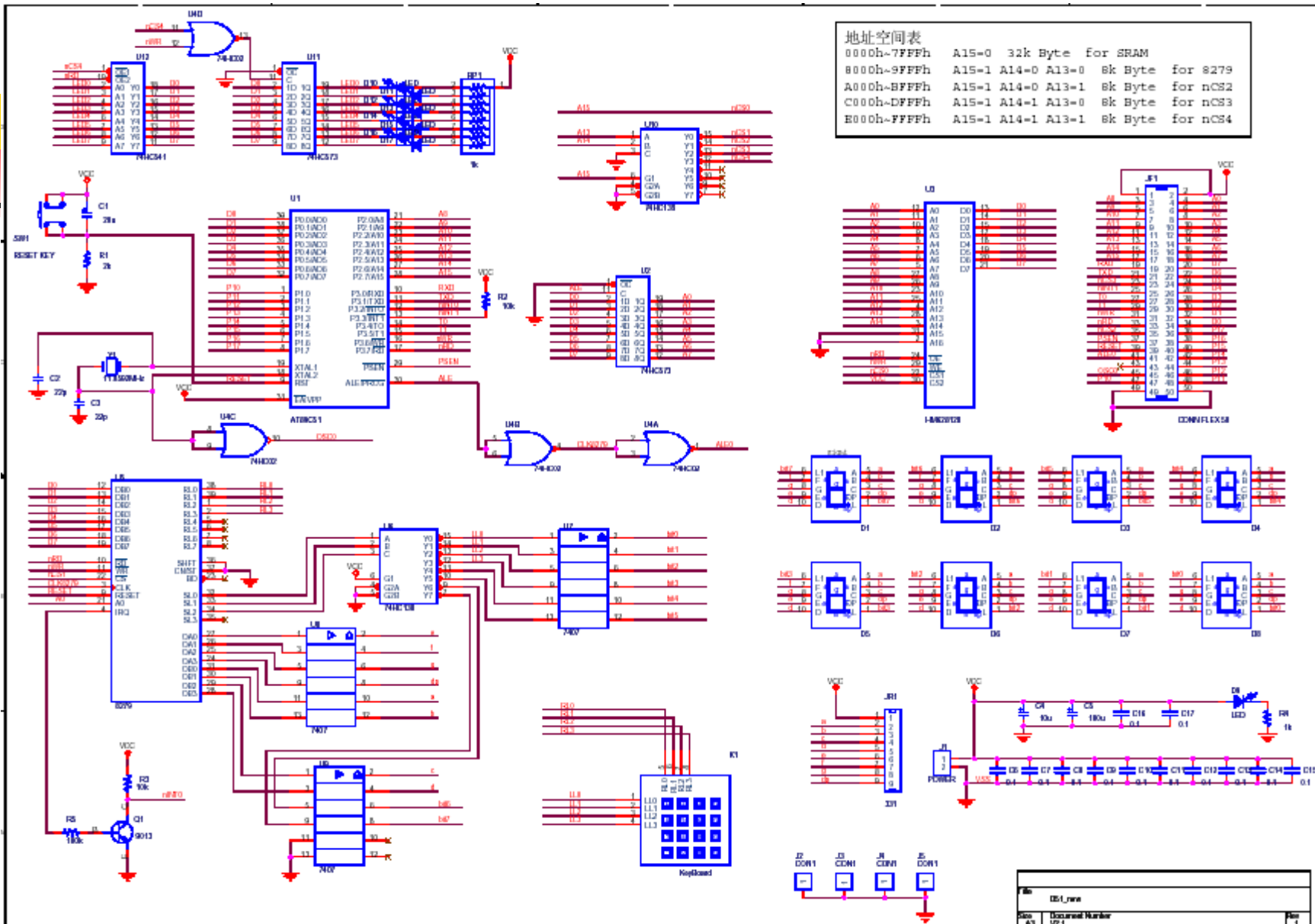
2. MCU Sub system Diagram(1)



3.3 Case Study 3: Sub System Design(2)

3. MCU Sub system Diagram(2)







3.3 Case Study 3: Sub System Design(3)

- n Digital Sub System
- n Measure Core



3.3 Case Study 3: Sub System Design(3)

1. Requirement for Measure Core

n Function

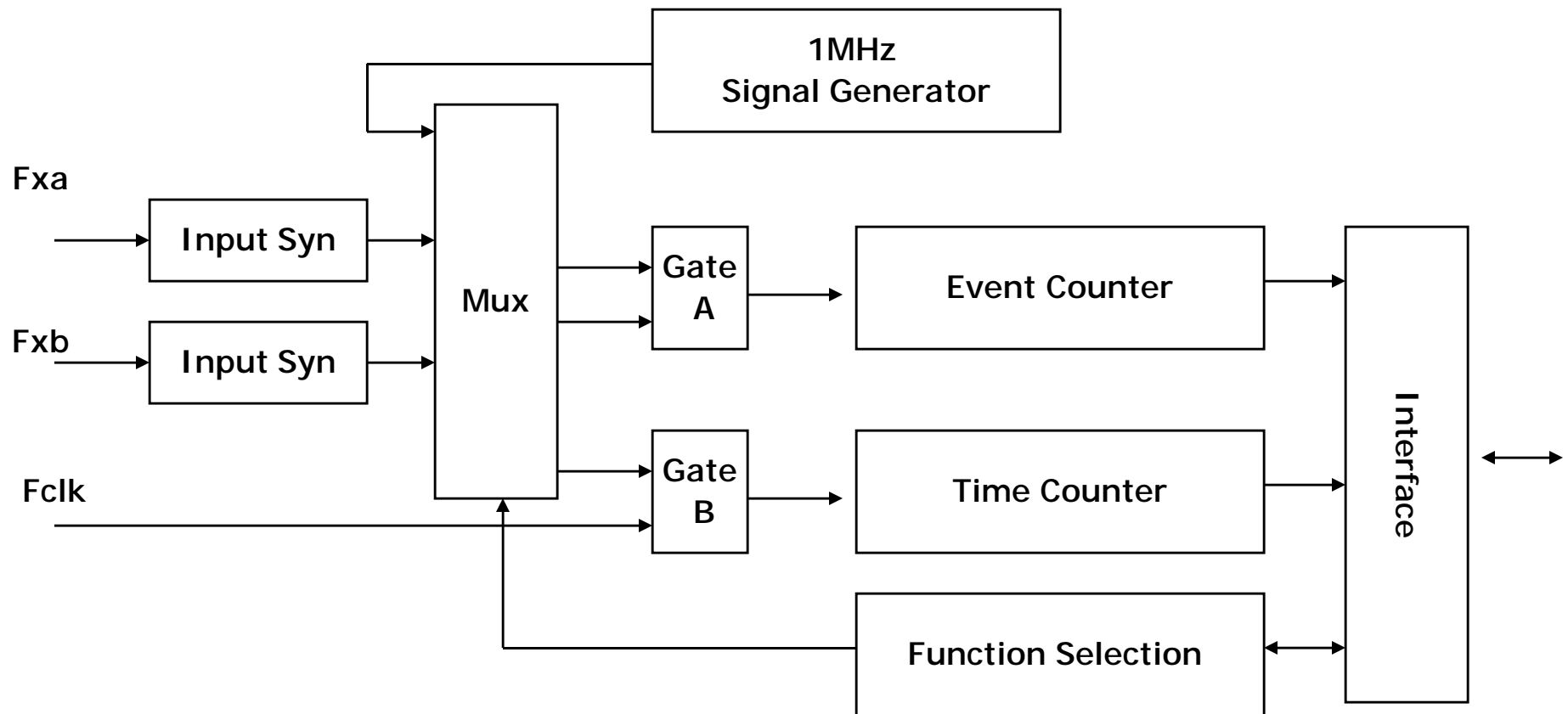
- n Multicycle Synchronization Measure Core
- n Measure Function Selection
 - n Frequency, Period, Time
- n 1MHz Signal Generator

n Specification

- n $F_{clk} = 10\text{MHz}$
- n $F_x = 10\text{ MHz}$
- n Measure Precision

3.3 Case Study 3: Sub System Design(3)

2. Measure Core Diagram



3.3 Case Study 3: Sub System Design(3)

3. Implementation Technology

	Speed	Flexibility	Debug	Capacity
MCU	Low	Good	Easy	Limit
MSI,SSI	Middle	Bad	Bad	Low
PLD	High	Good	Good	High

3.3 Case Study 3: Sub System Design(3)

4. Design Methodology

n Schematics

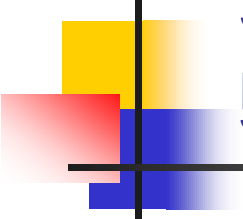
n VHDL

n Verilog

The screenshot displays the Quartus II IDE interface. The main window shows the VHDL code for the EPOCH_COUNTERS entity. The code includes library declarations for IEEE standard logic and numeric types, followed by the entity definition and its port list. The ports are: SYSCLK (16.368M), NRST (system), TIC (TIC sig), DUMP (DUMP si), EPOCH_LOAD_ENA (enable), EPOCH_LOAD (10 downto 0), EPOCH_CHECK (10 downto 0), and EPOCH (10 downto 0).

Below the code editor, a timing diagram is visible, showing the signals epoch_1ms_coun, epoch_20ms_cou, EPOCH, EPOCH_CHECK, and EPOCH_LOAD. The signals are represented as digital waveforms over time, with the EPOCH signal showing a periodic square wave pattern.

```
1 library ieee;
2 use ieee.std_logic_1164.all;
3 use ieee.numeric_std.all;
4 use IEEE.std_logic_UNSIGNED.all;
5
6 entity EPOCH_COUNTERS is
7 port (
8     SYSCLK:          in std_logic;          -- 16.368M
9     NRST:            in std_logic;          -- system
10    TIC :             in std_logic;          -- TIC sig
11    DUMP:             in std_logic;          -- DUMP si
12    EPOCH_LOAD_ENA:  in std_logic;          -- enable
13    EPOCH_LOAD:       in std_logic_vector(10 downto 0); --
14    EPOCH_CHECK:      out std_logic_vector(10 downto 0); -- e
15    EPOCH:            out std logic vector(10 downto 0) -- e
```

3.3 Case Study 3: Sub System Design(3)

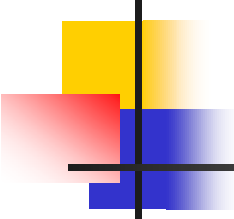
5. Digital Subsystem Design Main Points

- n Requirement Study & Analysis
- n Subsystem Diagram
- n Technology Selection
- n Module Design/Debug
- n Subsystem Debug



3.3 Case Study 3: Sub System Design(4)

n Power Sub System



3.3 Case Study 3: Sub System Design(4)

1. Requirement for Power Subsystem

- n Functions

- n Inputs

- n DC/AC

- n Outputs

- n Analog/Digital/RF/Driving

- n Power Model

- n ON/OFF, Wake/Sleep/Battery

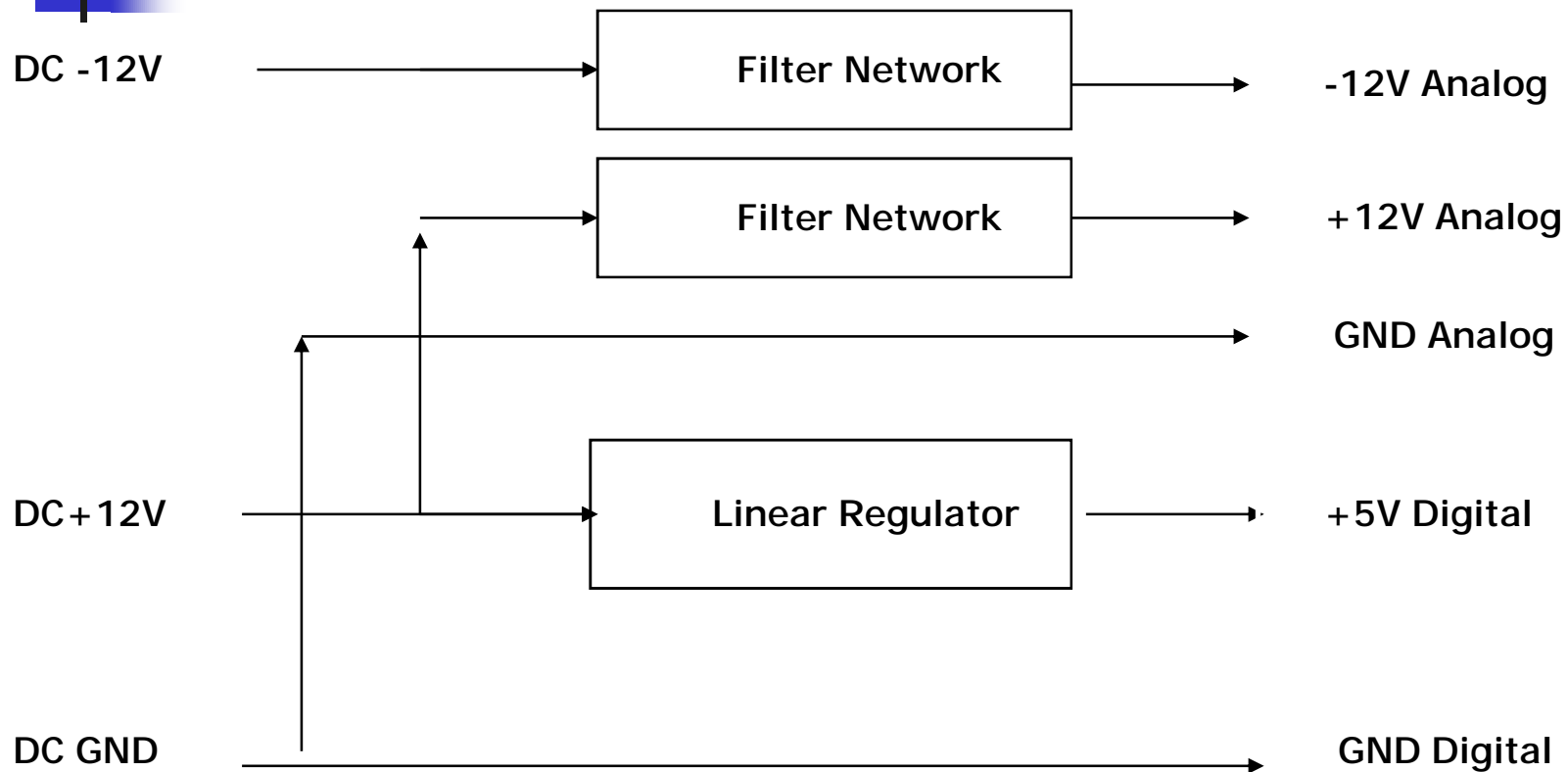
- n Specifications

- n Voltage/Noise

- n Current/Max

3.3 Case Study 3: Sub System Design(4)

2. Power Subsystem Diagram





3.3 Case Study: Sub System Design Summary

- n Requirement Study & Analysis
- n Algorithm Selection
- n System Diagram
- n Module Circuit Design
- n **Double Check**



3.4 Case Study 4: Software Design

1. Requirement for Software Subsystem

- n Function

- n Reset

- n Read Keyboard

- n Control the Measure Core

- n Freq,Period,Duty...

- n Read Measure Data

- n Data Process

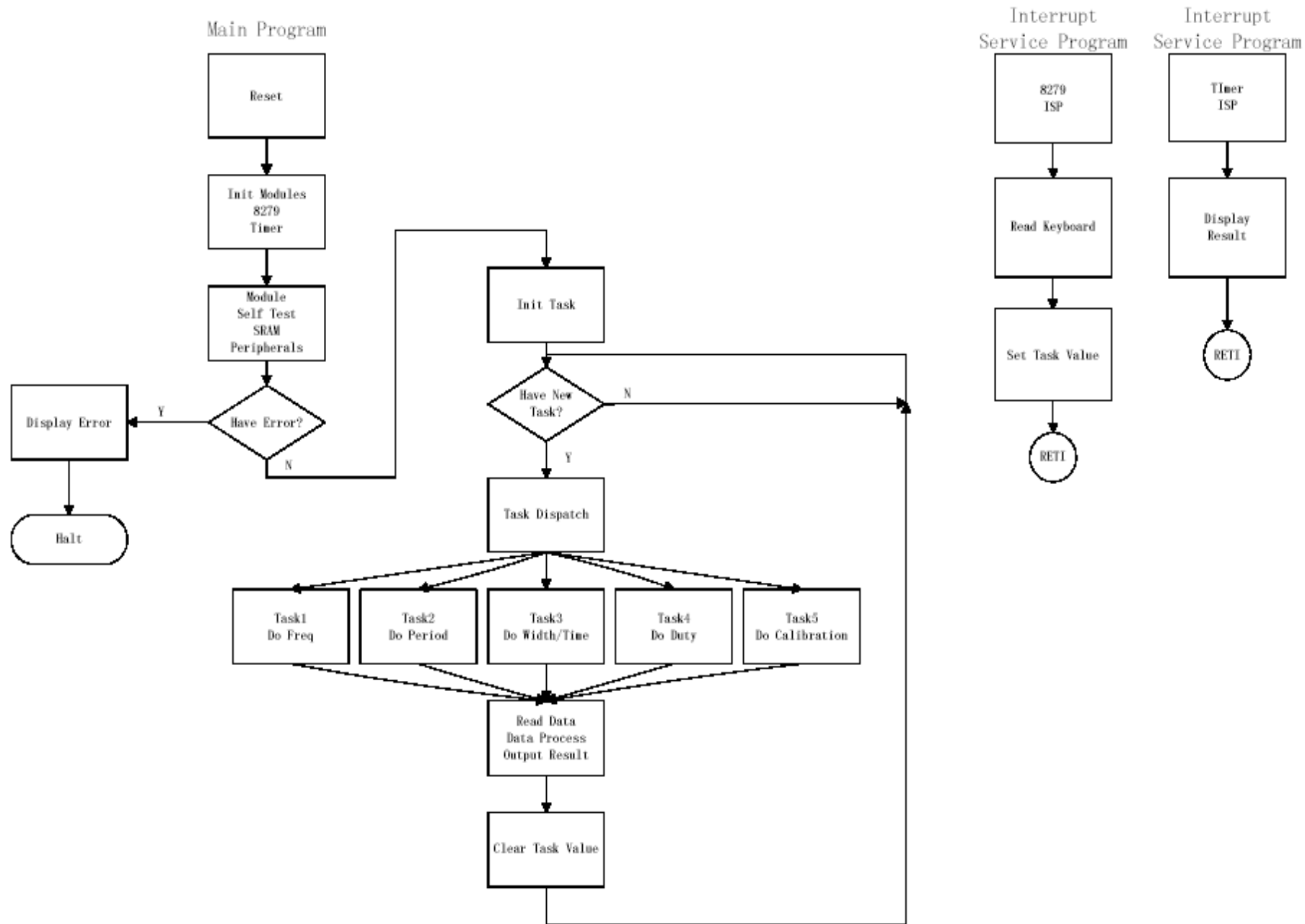
- n Display Result



3.4 Case Study 4: Software Design

2. Diagram/Modules

- n Modular Design
 - n Main Program
 - n Reset
 - n Init Modules/Self Test
 - n Init Task
 - n Task Dispatch
 - n Task Program
 - n Task1: Do Frequency
 - n Task2: Do Period
 - n Task3: Do Width/Time
 - n Task4: Do Duty
 - n Task5: Do Self Calibration
 - n Sub Program
 - n Read Data
 - n Data Process
 - n Output Result
 - n Interrupt Program
 - n Read Keyboard/Display Data

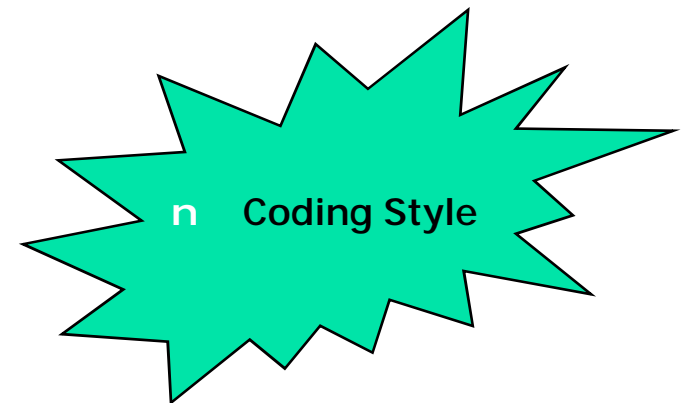




3.4 Case Study 4: Software Design

4. MCU Software Design Main Points

- n Requirement Study
- n Task List
- n Diagram/Modules
 - n Main Program
 - n Task Program
 - n Public Sub Program
 - n Interrupt Service Program
- n System FlowChart
 - n Task Driving Architecture
- n Program/Debug
- n Integrate





3.4 Case Study 4: Software Design

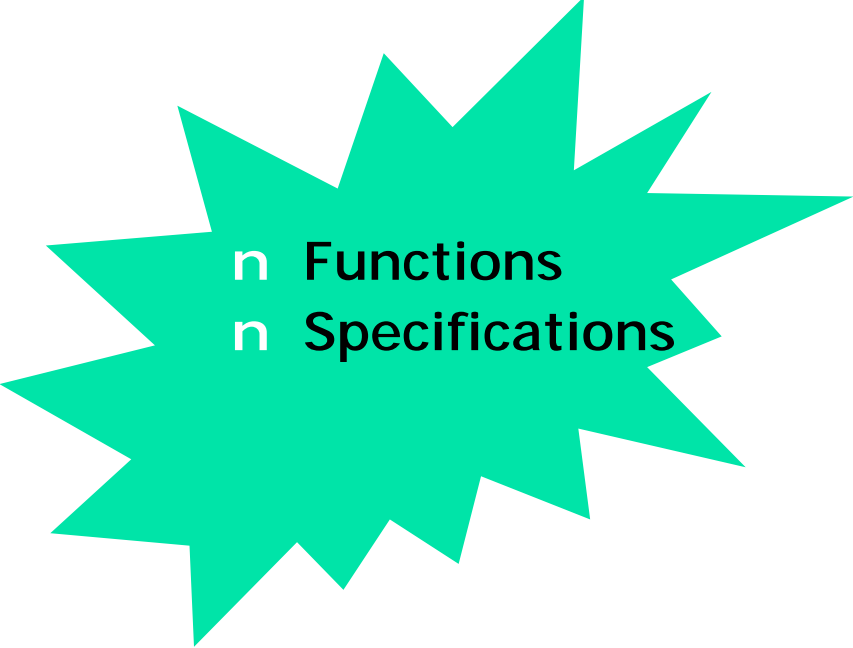
5. Fault-tolerant Design

- n Reset
 - n Flags to distinguish the reason
- n Watch Dog
 - n Hardware Counter
 - n Software trigger
- n Soft Trap
- n Redundancy of Instruction
- n Digital Filter:
 - n Median Filter for AD data

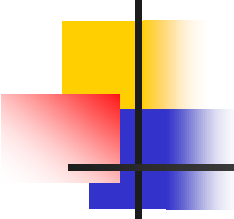
3.5. Case Study 5: System Test

1. Requirement

- n System Test
 - n Function
 - n Specifications



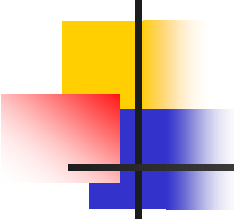
n Functions
n Specifications



3.5 Case Study 5: System Test

2. System Test Bench

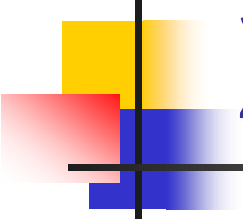
- n Instruments
 - n Signal Generator
 - n Counter
 - n Voltage meter
 - n Oscilloscope
- n Methodology
 - n Manual
 - n Record Data



3.5 Case Study 5: System Test

3. Subsystem Test

- n Input Channel Test
- n Measure Core Test
- n MCU Subsystem Test
- n Software Test
 - n Task Program
 - n Sub Program
 - n Interrupt Program
 - n Main Program



3.5 Case Study 5: System Test

4. System Test

- n System Test
 - n Function
 - n Specifications
- n Data Analysis
 - n Error Analysis



n Functions
n Specifications



3.6 Case Study 6: Document 1.Requirement

（一）→ **摘要**

对本项目及完成情况的概要介绍，关键词。

（二）→ **系统方案论证**

对本项目采用的系统方案进行论证，要有多种方案的比较，给出所采用方案的系统框图。

（三）→ **理论分析与计算**

对本项目采用的部件（元器件）、方法、算法进行理论分析与计算，证明其符合要求。

（四）→ **重要电路设计**

对本项目采用的关键电路进行设计分析、比较，给出原理图。

（五）→ **软件流程**

软件流程图、模块说明。

（六）→ **系统功能及使用方法**

类比使用说明书。

（七）→ **系统测试及结果分析**

给出测试方法、所使用仪器、测试数据及测试结果分析（误差分析）。

（八）→ **进一步讨论**

系统性能的进一步改进措施等。

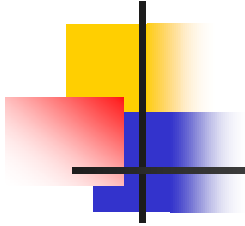
（九）→ **结束语**

3.6 Case Study 6: Document

2.Example:低频数字式相位测量仪

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n 4. Design Tips



4. Design Tips

1. 系统设计

- n 可制造性设计 (DFM)
 - n 设计容差, 边界条件和极限参数
 - n 器件不同的封装、来源
- n 可测试性设计(DFT)
 - n 预先考虑调试,
 - n Example: 预留测试点, 闭环电路的开环断口
 - n 可以自测试 (Self-Test)
- n 可扩展性设计
 - n 基本+发挥
 - n Example: 设计余量, 接口



1. 系统设计

- n 模块化设计
 - n 可替换，可单独调试
 - n 功能单一
 - n 连线简单
 - n Example:
 - n AD/DA 模块
 - n 电源模块
 - n ○ ○ ○

4. Design Tips

2. 新器件的使用

- n Example:

- n 单片机选用

- n 8051

- n Intel: 8031

- n Atmel: Flash+PW+WD

- n Philips: 33M+CAN+AD

- n CYGNAL: SOC: JTAG+8051+AD+温度

- n AVR: RISC+ ISP + C +Low Power+AD

- n PIC

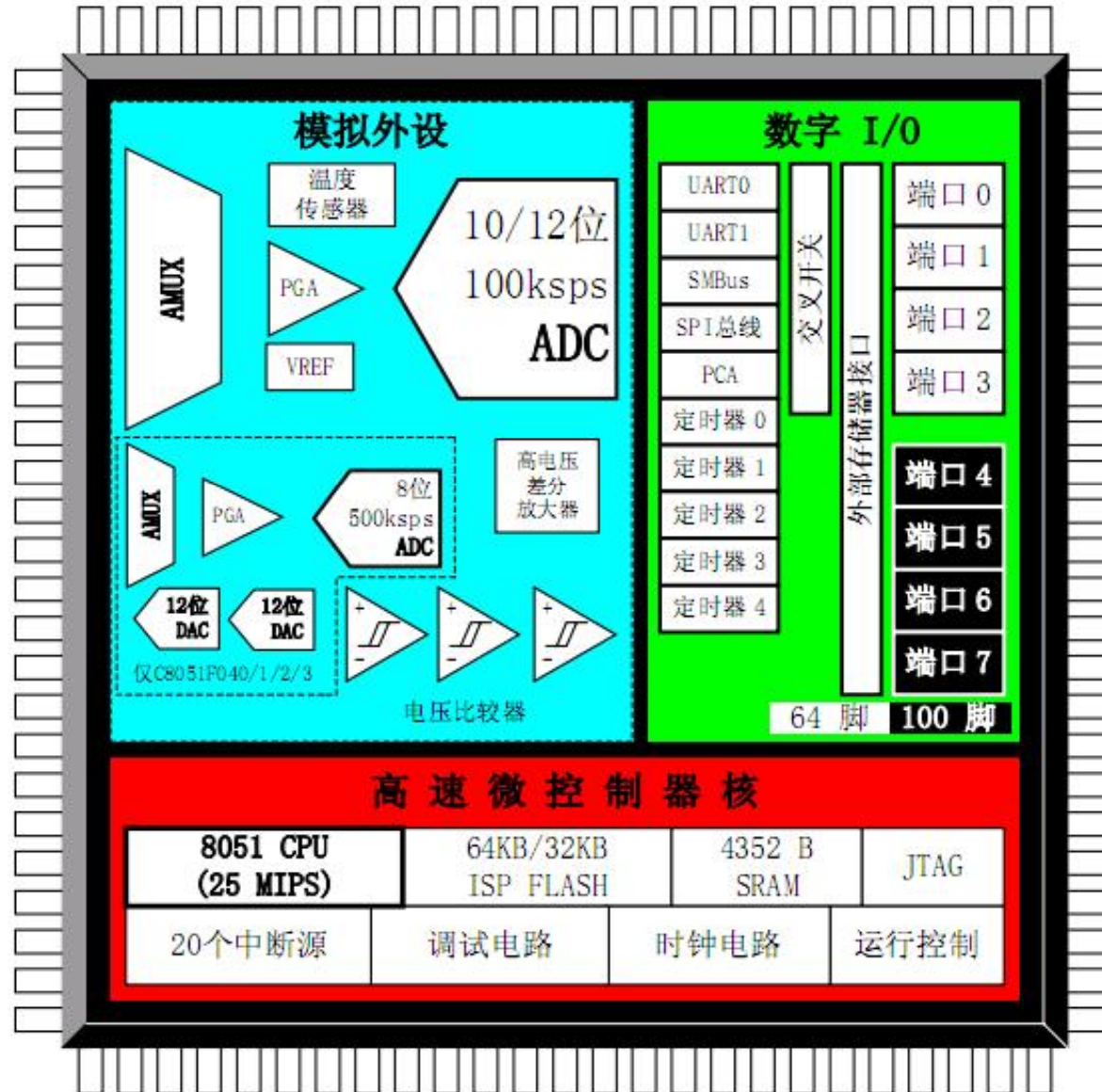
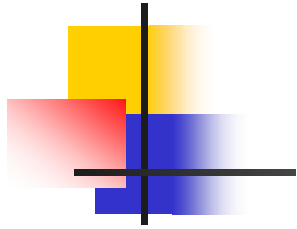
- n Motorola 68H

- n Scenix单片机 : 50M

- n 工作温度范围

- n 民用级0°C~70°C，工业级是-40°C~85°C，军用级是-55°C~125°C

C8051F040





4.Design Tips

3. Debug

- n 全局检查

- n 电源短路，接线错误

- n 逐步调试

- n 逐级逐块安装，逐步调试



4.Design Tips

4. Analog Circuit Debug

- n 晶体管电路
 - n 检查工作点
 - n 断开级联，断开反馈
- n 运放
 - n 差分输入端电位
 - n 自激
 - n 最好不要超过2级



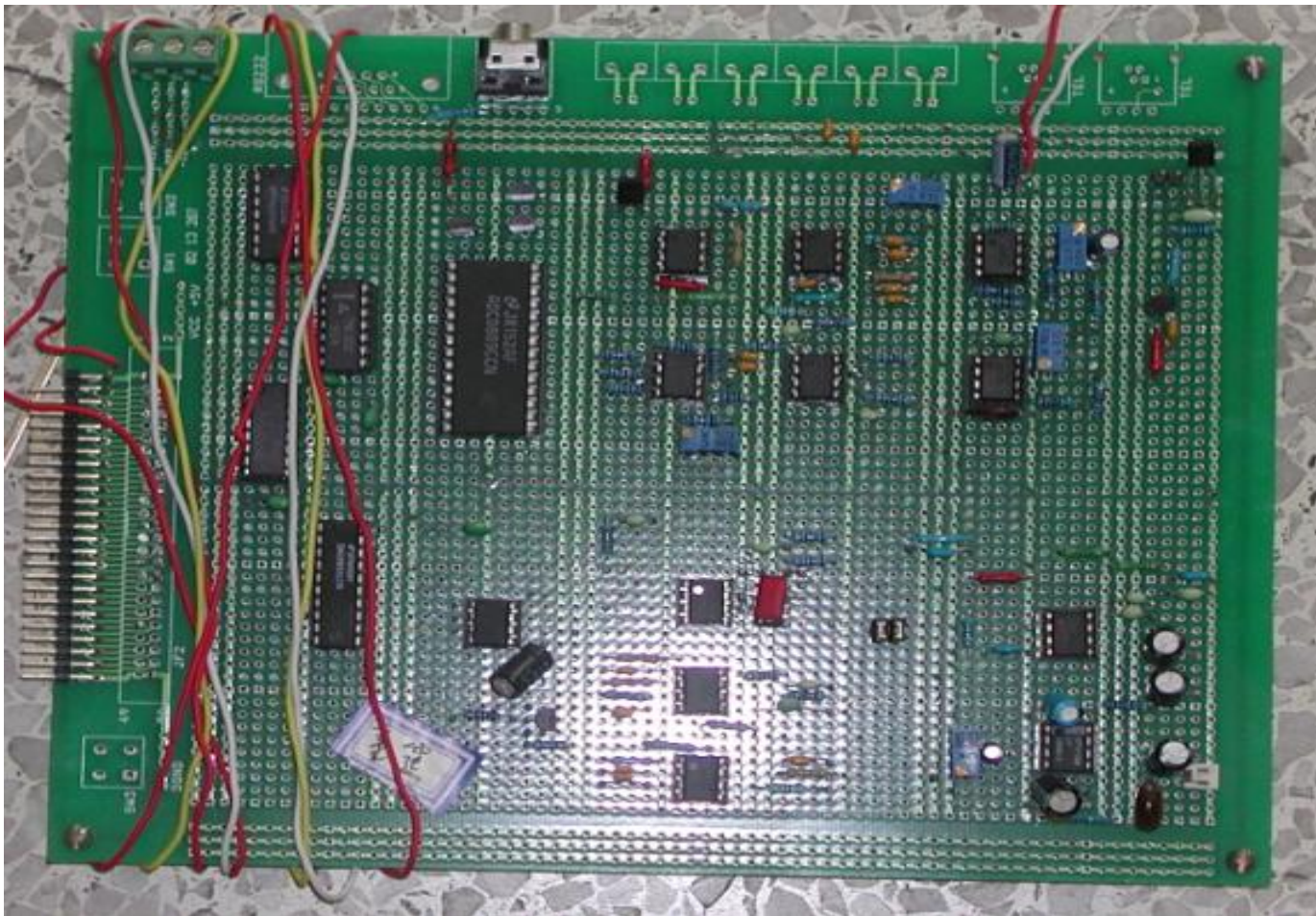
4.Design Tips

5. PCB布线原则

- n 布局均衡
- n 电源线、地线尽可能粗
- n 数字，模拟电路分开，地线不要混叠
- n 低频一点接地，高频多点接地
- n 电源滤波
 - n 输入处接一个100uF电解电容
 - n 每个集成电路电源接0.01uF小电容
 - n 串接电感（铁氧芯）
- n 相关器件靠近，接线短
- n 散热要求

4.Design Tips

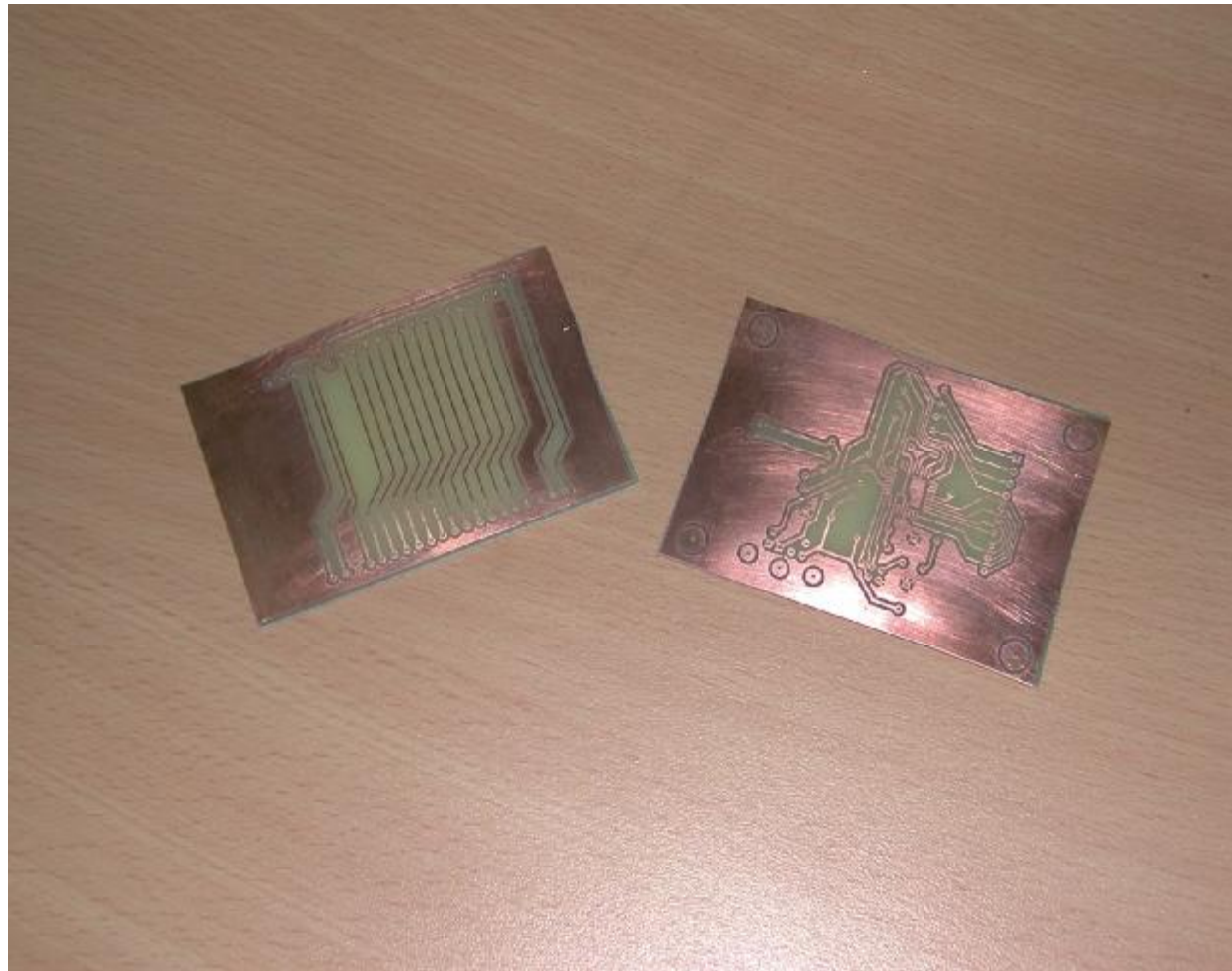
6. PCB布线原则： Example



EE109 Electronic System Design

4.Design Tips

6. PCB布线原则: Example



EE109 Electronic System Design

4.Design Tips

7. 可靠性测试

n 系统自测试

n 测试单片机软件功能的完善性

n 上电掉电测试

n 老化测试

n 电磁测试

n 静电试验(ESD)

n 空间辐射耐受试验(RS)

n 快速脉冲抗扰测试(EFT/B)

n 雷击试验(Surge)

n 传导抗扰耐受性(CS)

n 脉冲耦合 (Impulse)



系统指标之一!!



4.Design Tips

8. Reference Design Source

- n [ftp.ele.pku.edu.cn](ftp://ftp.ele.pku.edu.cn)
 - n Lecture
 - n Schedule
 - n Name list
 - n System Board Schematics:
 - n D51_sch.pdf
 - n Test program:
 - n Board_test.asm
 - n IC Material List
 - n Ic_list.txt

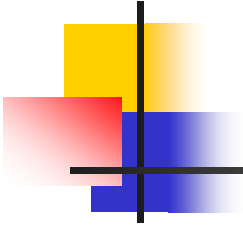


4.Design Tips

10. Reference Design resources

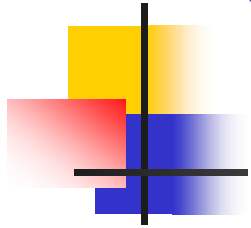
n Websites

- | | |
|--|-------------------|
| n www.21ic.com | IC & Paper |
| n www.icminer.com | IC |
| n www.zlgmcu.com | 8051 |
| n www.altera.com.cn | CPLD/FPGA |
| n www.analog.com | AD analog devices |
| n www.maxim-ic.com.cn | maxim IC |
| n www.ti.com.cn | TI IC |

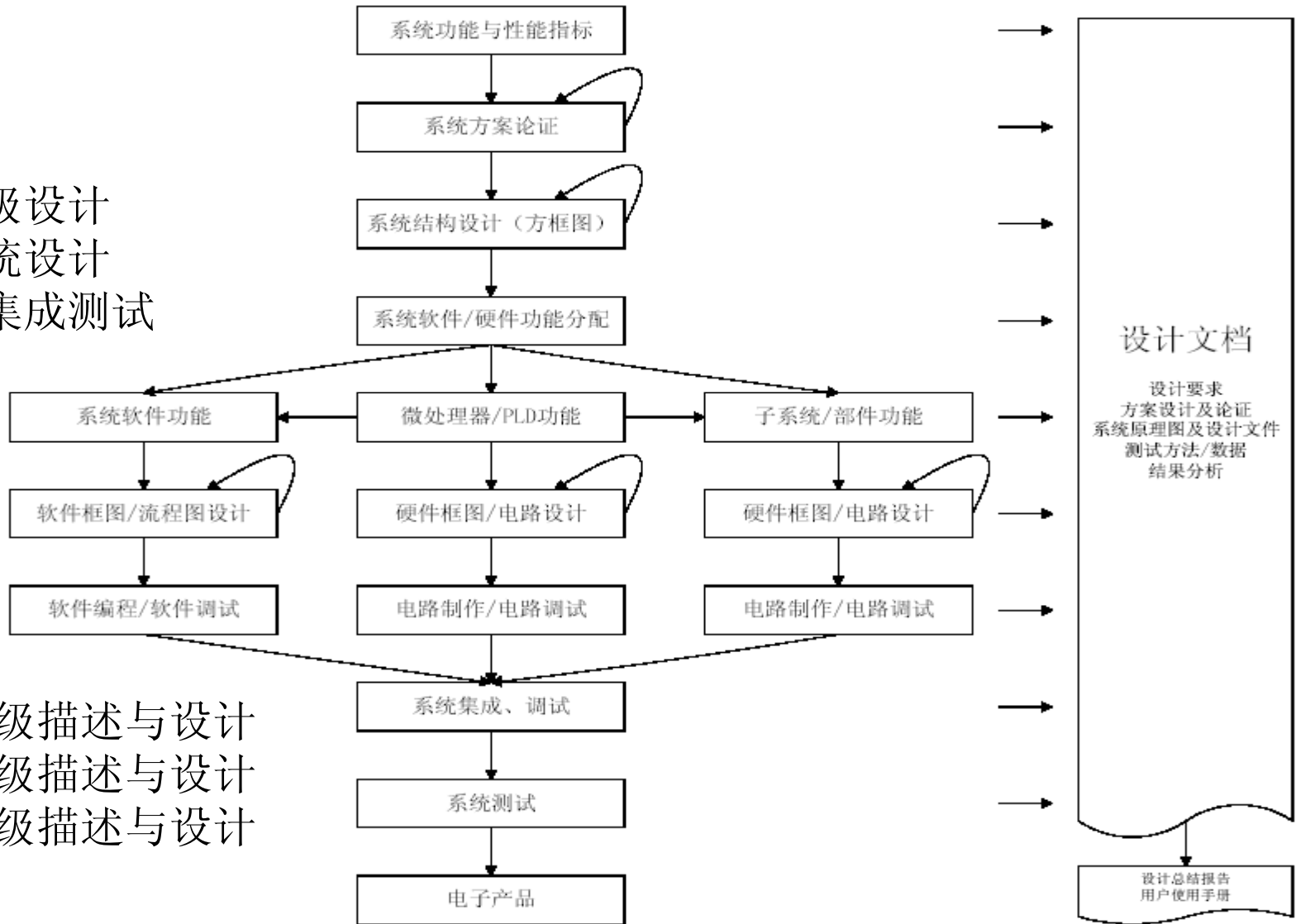


n 5. Summary

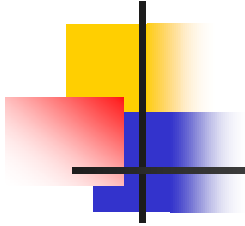
Process of Design



- 系统级设计
- 子系统设计
- 系统集成测试



- 行为级描述与设计
- 结构级描述与设计
- 物理级描述与设计



n Q/A?